

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
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Examiner		Art Unit	Cynthia Britt	
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*	B	US-6,272,588	08-2001	Johnston et al.	711/106
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	V	"Quick Address Detection of Anomalous Memory Cells in a Flash Memory Test Structure" by Himeno, et al. IEEE Transactions on Semiconductor Manufacturing, Publication Date: May 1997 Volume: 10, Issue: 2 pages: 196-200 INSPEC Accession Number: 5570257
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.